COIN TRUNK CIRCUIT SD-31592-02 AND AUXILIARY COIN TRUNK CIRCUIT SD-32538-01 ARRANGED FOR DIAL-TONE-FIRST SERVICE OPERATION TESTS USING TEST SET SD-31858-01 (J34701A) STEP-BY-STEP SYSTEMS

1. GENERAL

1.01 This section describes a method of testing the operating features of the coin trunk circuit (SD-31592-02) and auxiliary coin trunk circuit (SD-32538-01) arranged for dial-tone-first service using test set SD-31858-01 (J34701A). Information in this section was formerly contained in Section 226-521-501.

1.02 This section is reissued to revise paragraph 1.05 to include information on sleeve identification when performing Test E in offices equipped with ANI. This issue does not affect the Equipment Test List.

1.03 The tests covered are:

PAGE

A. Coin Test: This test checks the ability of the auxiliary coin trunk circuit to recognize that a coin has been deposited. 6

B. Coin Collect—Loop: This test checks the coin collect features of the auxiliary coin trunk and coin trunk while under a loop condition. . . . 8

C. Coin Collect—Loop Using Connector Test Line SD-31857-01, Fig. 3 (99 Terminal): This test checks the coin collect features of the auxiliary coin trunk and coin trunk while under loop condition. 11

D. Coin Return—Leak: This test checks the coin return features of the auxiliary coin trunk and coin trunk while pulsing under a leak condition. . 15

E. Operator Cut-Through and Ringback: This test checks the metallic cut-through over which the operator controls the coin and also the features that provide the operator with a means of holding a trunk and ringing back through it. 16

F. P1 Relay Release Test: This test checks the ability of the P1 relay in the coin trunk to release satisfactorily under an open circuit condition. 19

G. Stuck-Coin Alarm Test: This test checks that the stuck-coin alarm feature of the auxiliary coin trunk and coin trunk function satisfactorily. . 23

H. Coin-Trunk-Timed-Release Circuit Test (SD-31861-01): This test checks that the coin-trunk- timed-release circuit will release the coin trunk when a stuck-coin condition is applied. . 24

1.04 These tests should preferably be made during periods of light traffic, and the performance of Test E should be coordinated with the group responsible for operator services.

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1.05 During Test E, when testing to a TSPS office, and automatic number identification (ANI) equipment is provided in testing office, ▶a sleeve identification will have to be provided to prevent◀ second trial transverter failure registrations. ▶(See Fig. 1 for example of providing this sleeve identification.)◀

1.06 The test set is not designed to make an operate test of the P1 relay. Whenever circuit operation indicates a need, the P1 relay should be adjusted in accordance with the Circuit Requirements Table of SD-31592-02.

1.07 When testing coin trunks equipped with coin-trunk-release circuit (SD-31861-01), test each trunk in accordance with procedures of Test G; then test each trunk in accordance with procedures of Test H.

1.08 During Test H, the check of the coin-trunk-timed-release circuit register, if provided, will cause the register to advance. The reporting of this register operation should be in accordance with local instructions.

1.09 When making the coin-trunk-timed-release circuit (SD-31861-01) ineffective in an office arranged for extending alarms to another office, operate audible alarm switch or key to a position where audible alarm will be heard. For offices not arranged for extending alarms, at coin-trunk-timed-release circuit (SD-31861-01), turn CO key to a position where GD lamp lights. Some offices may have circuit arrangements which do not furnish key control. In this case it will be necessary to block coin-trunk-timed-release C relay in the nonoperated position.

1.10 When making the coin-trunk-timed-release circuit (SD-31861-01) effective in an office arranged for extending alarms to another office, operate audible alarm switch or key to a position that makes alarms extended to another office. Notify proper person in the distant office that alarms have been transferred. For offices not arranged for extending alarms, at coin-trunk-timed-release circuit (SD-31861-01), turn CO key to a position where GD lamp is extinguished.

2. TEST PROCEDURES

A. Apparatus

Tests A Through H

2.01 Test set J34701A (SD-31858-01) equipped with 2H and 2K options which provide an RCK key and CTCK lamp.

2.02 Head telephone set, 52-type.

2.03 Patching cords, two P3E cords, 6 feet long, equipped with red-shelled 310 plugs (3P7A cords).

Test F

2.04 If test set is equipped with a CL jack, and auxiliary coin trunk is located within cord distance of coin trunk, use a patching cord, 3P15B, consisting of one P3K cord, 12 feet long, equipped with two 310 plugs.

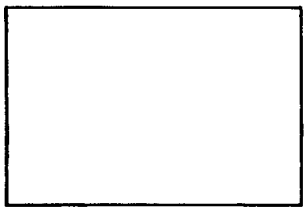
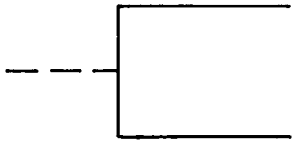
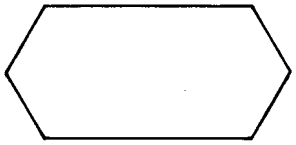
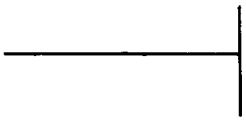
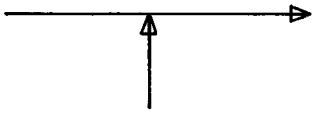
2.05 If auxiliary coin trunk is not located within cord distance of coin trunk or test set is not equipped with a CL jack, a special test cord, made up locally as shown in Fig. 2, must be used with test set. The physical arrangement of the lamp, key, and resistor can be determined locally. In offices where a battery and ground jack is not available, two KS-6780 connecting clips and two 108 cord tips should be used in place of the 310 plug with black shell.

B. Flowcharts

2.06 Table A provides an explanation of the symbols that are used in the test procedure flowcharts.

TABLE A

FLOW CHART EXPLANATIONS

SYMBOL	EXPLANATION
	Indicates the beginning of the procedure and an exit or entrance reference to pages within same procedure.
	Indicates an action which is performed on a manual or automatic basis.
	Brackets are used to reference supporting-type data.
	Used to represent a decision which determines which one of two paths to take.
	The end of procedure symbol is used to denote that the end of the emergency action condition has been completed.
	Used to indicate the direction of information flow.
	Used to indicate two processes flowing into a common sequence.

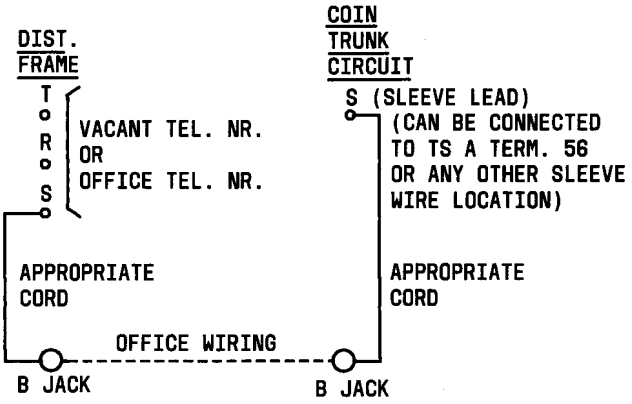


Fig. 1—Example of Connections Needed for Test E When Office is Equipped With ANI

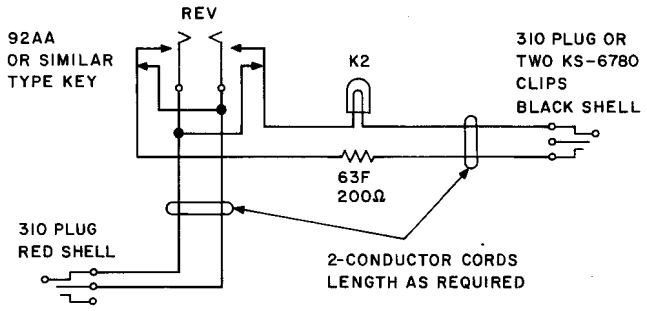


Fig. 2—Test Cord

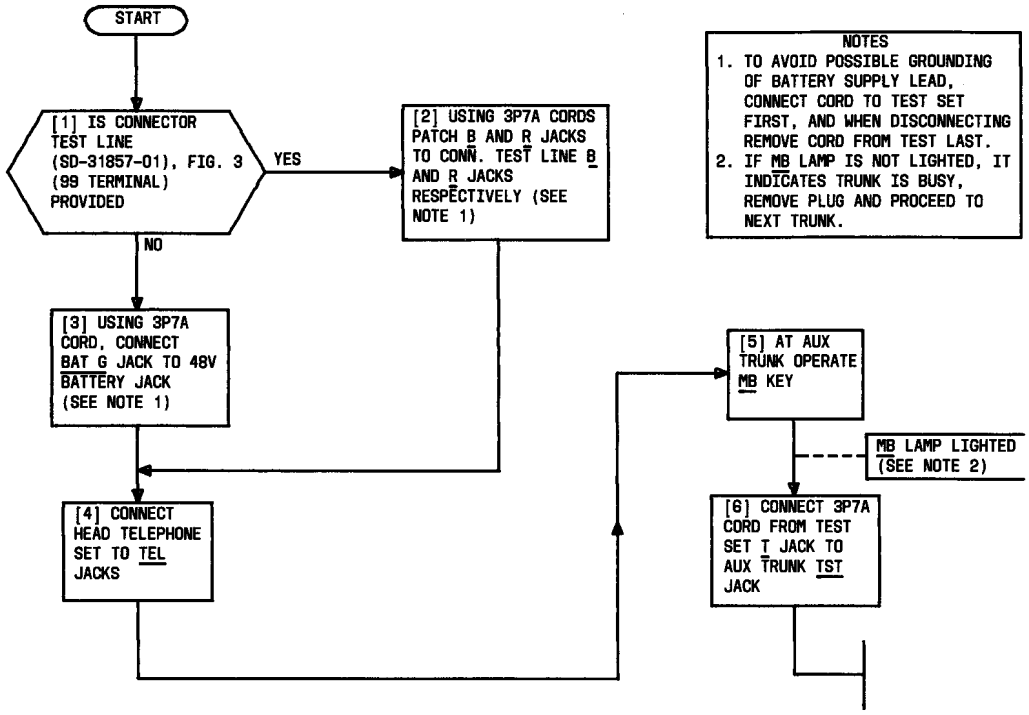


Fig. 3—Test Preparation

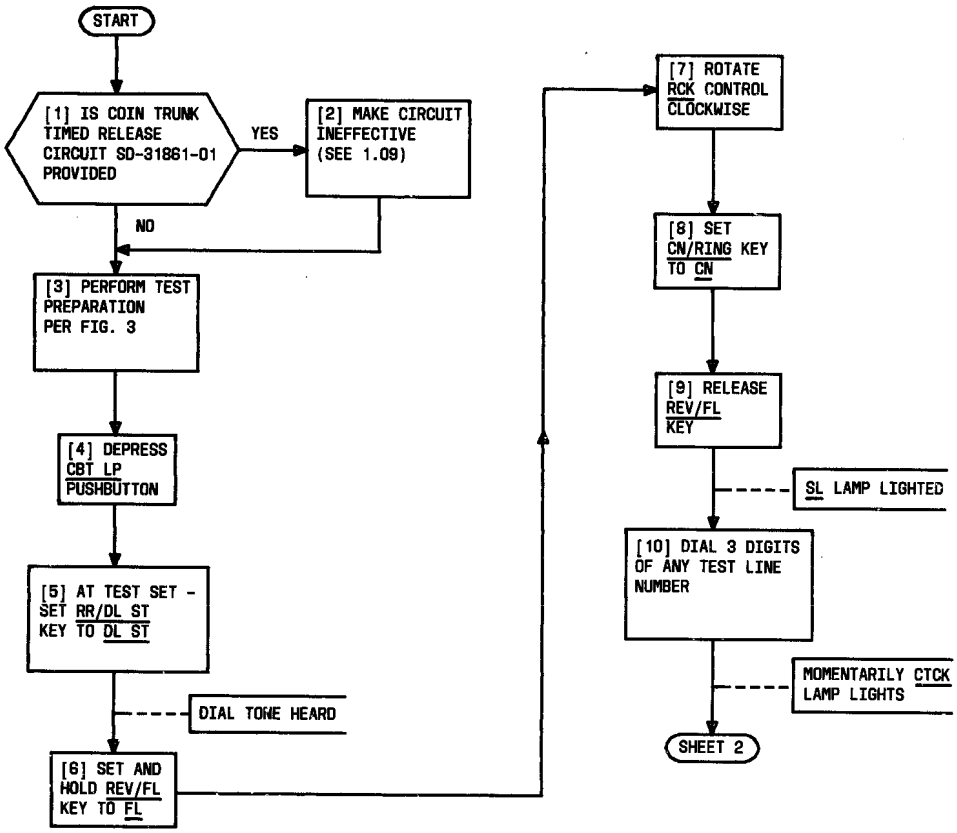


Fig. 4—Test A: Coin Test (Sheet 1 of 3)

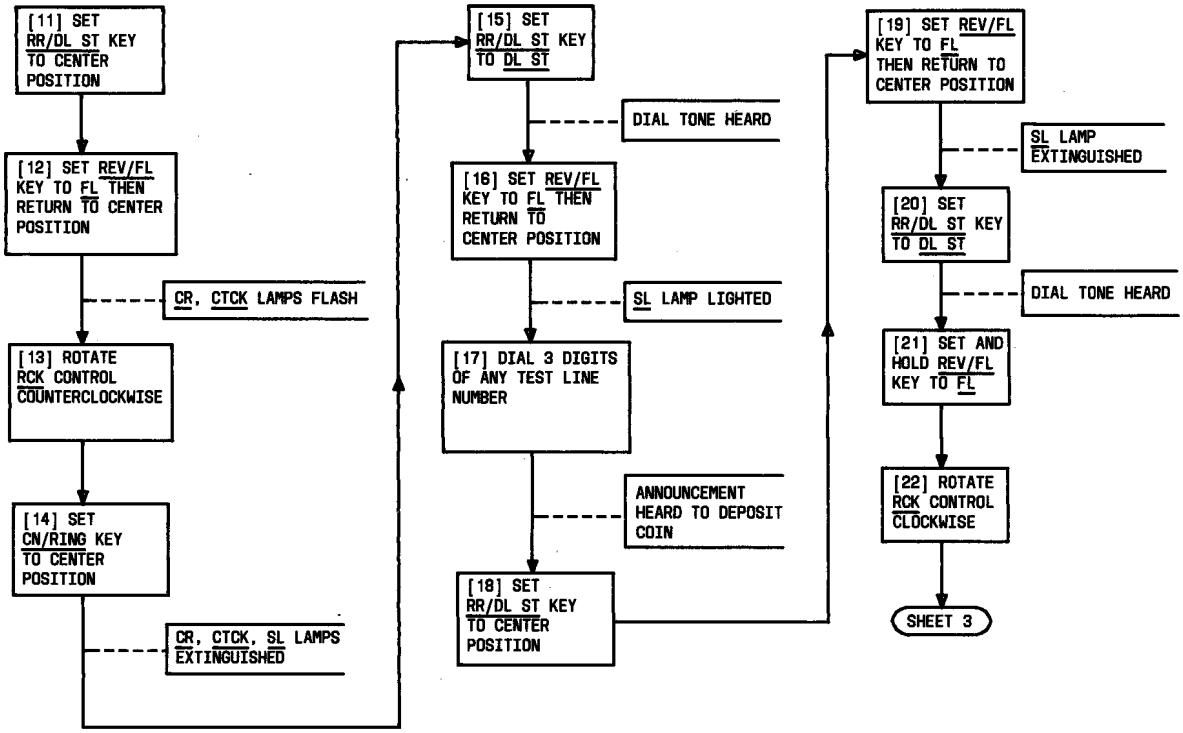


Fig. 4—Test A: Coin Test (Sheet 2 of 3)

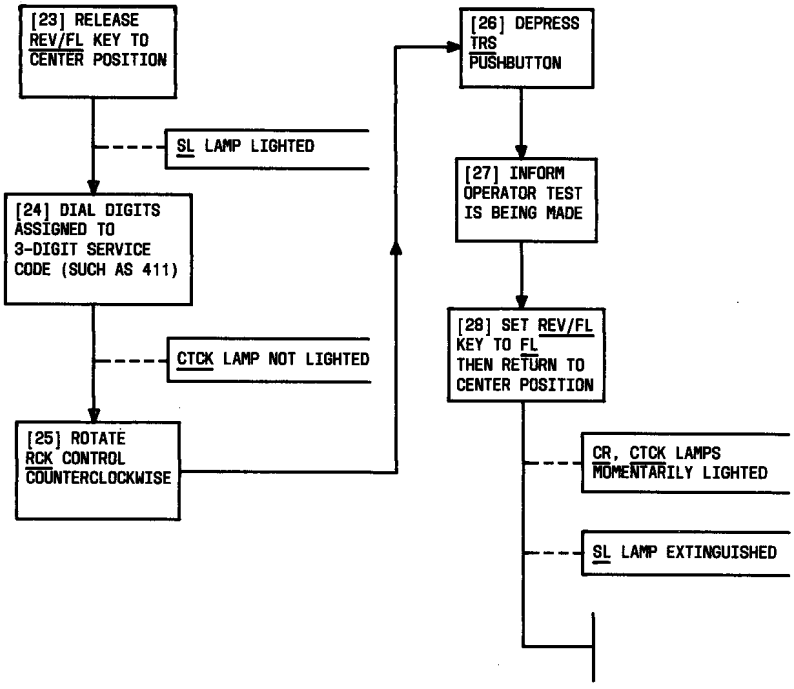


Fig. 4—Test A: Coin Test (Sheet 3 of 3)

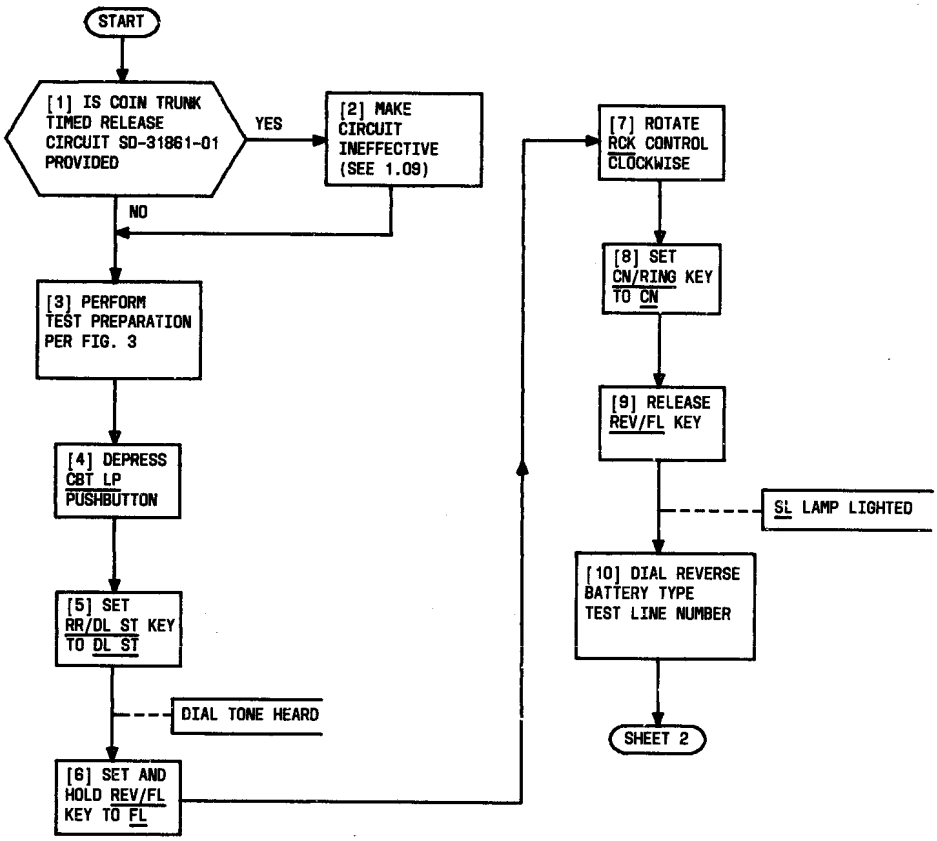


Fig. 5—Test B: Coin Collect-Loop (Sheet 1 of 3)

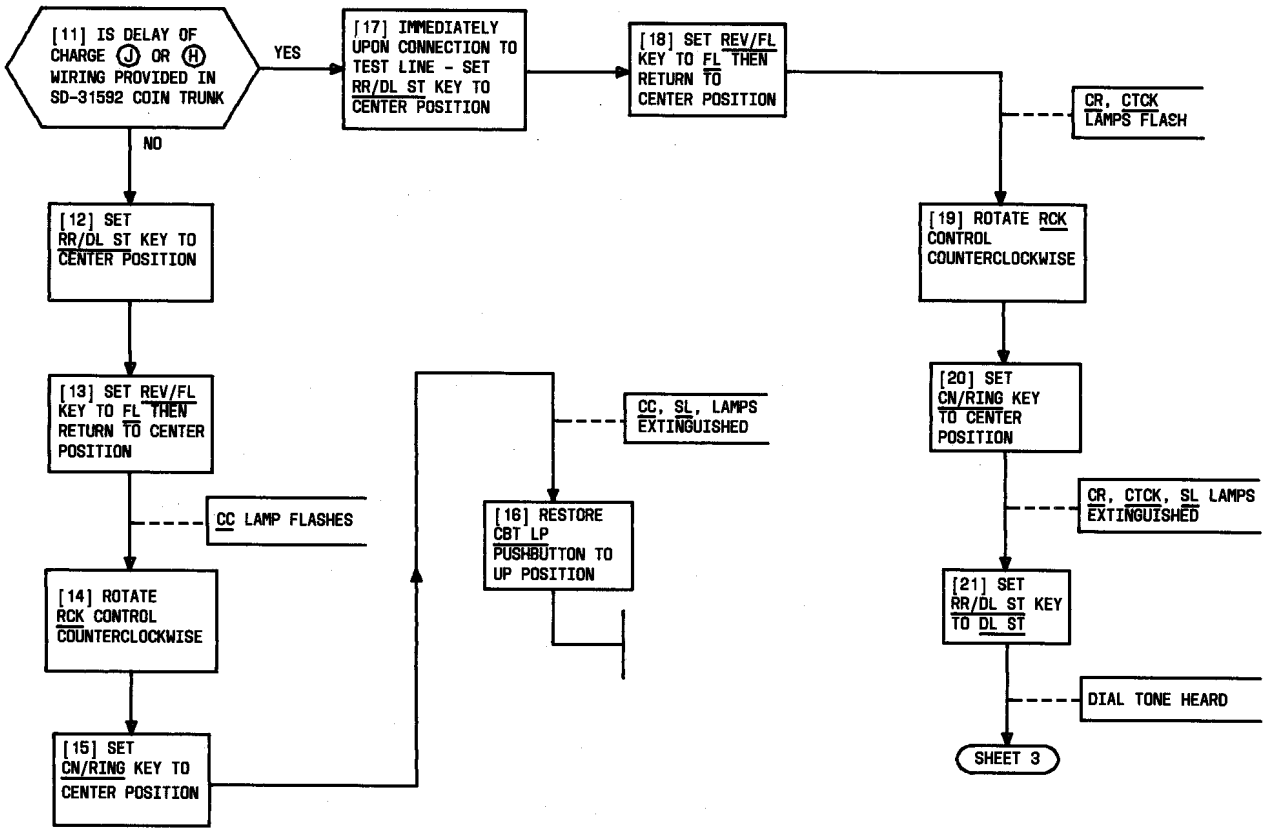


Fig. 5—Test B: Coin Collect-Loop (Sheet 2 of 3)

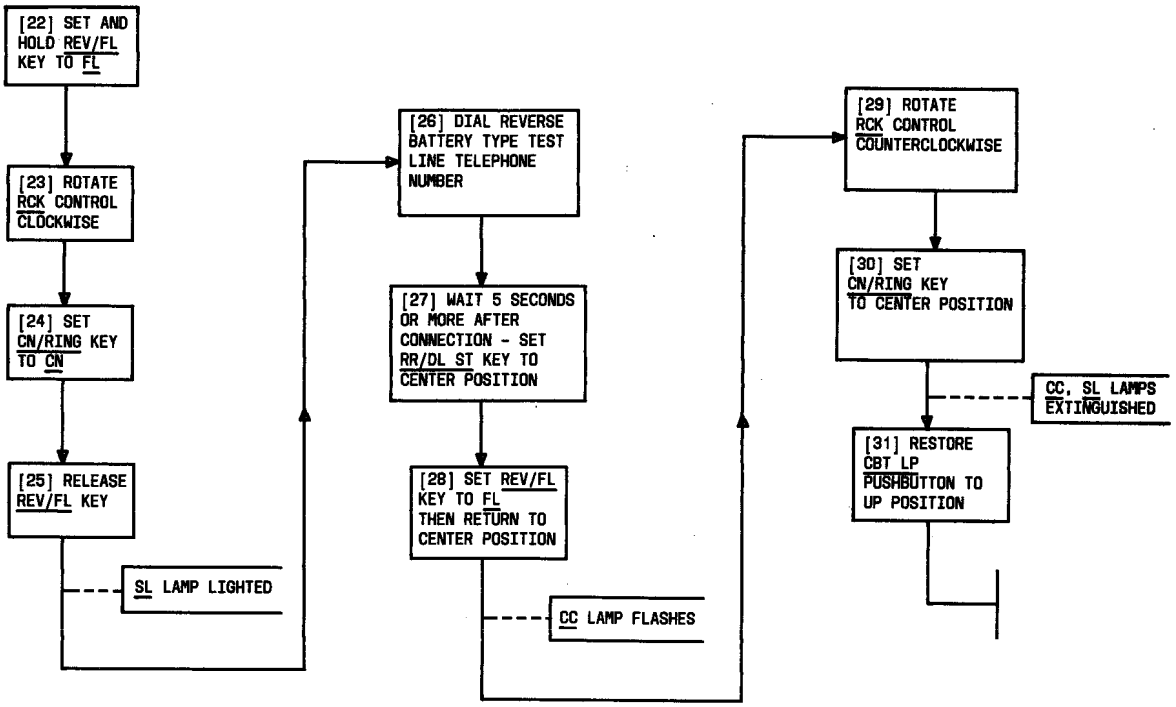


Fig. 5—Test B: Coin Collect-Loop (Sheet 3 of 3)

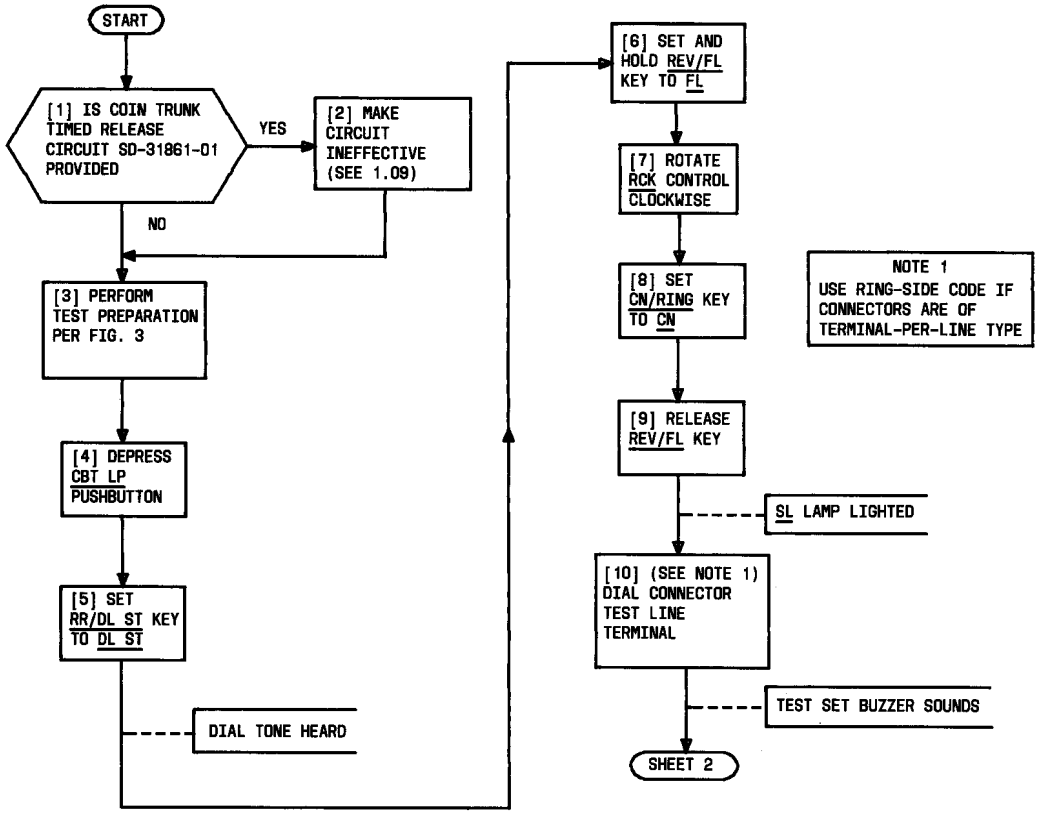


Fig. 6—Test C: Coin Collect-Loop Using Connector Test Line SD-31857-01 Fig. 3 (99 Terminal) (Sheet 1 of 4)

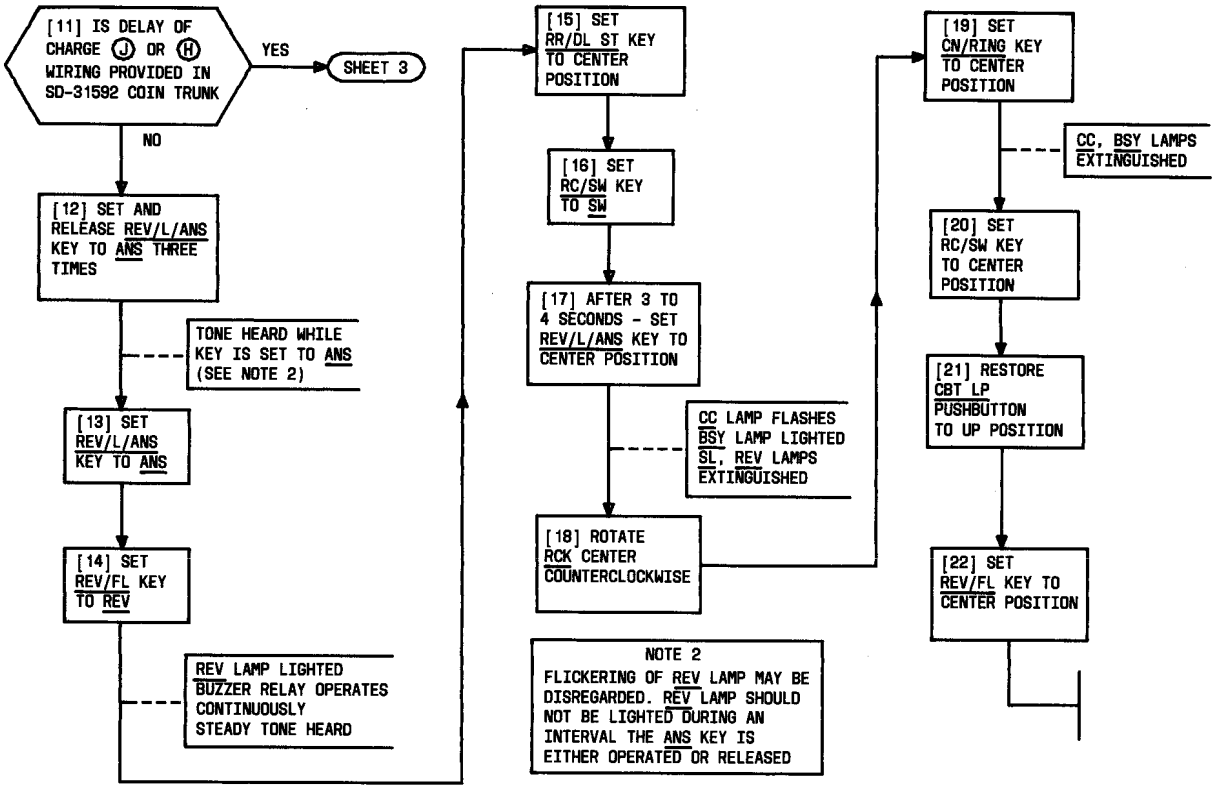


Fig. 6—Test C: Coin Collect—Loop Using Connector Test Line SD-31857-01 Fig. 3 (99 Terminal) (Sheet 2 of 4)

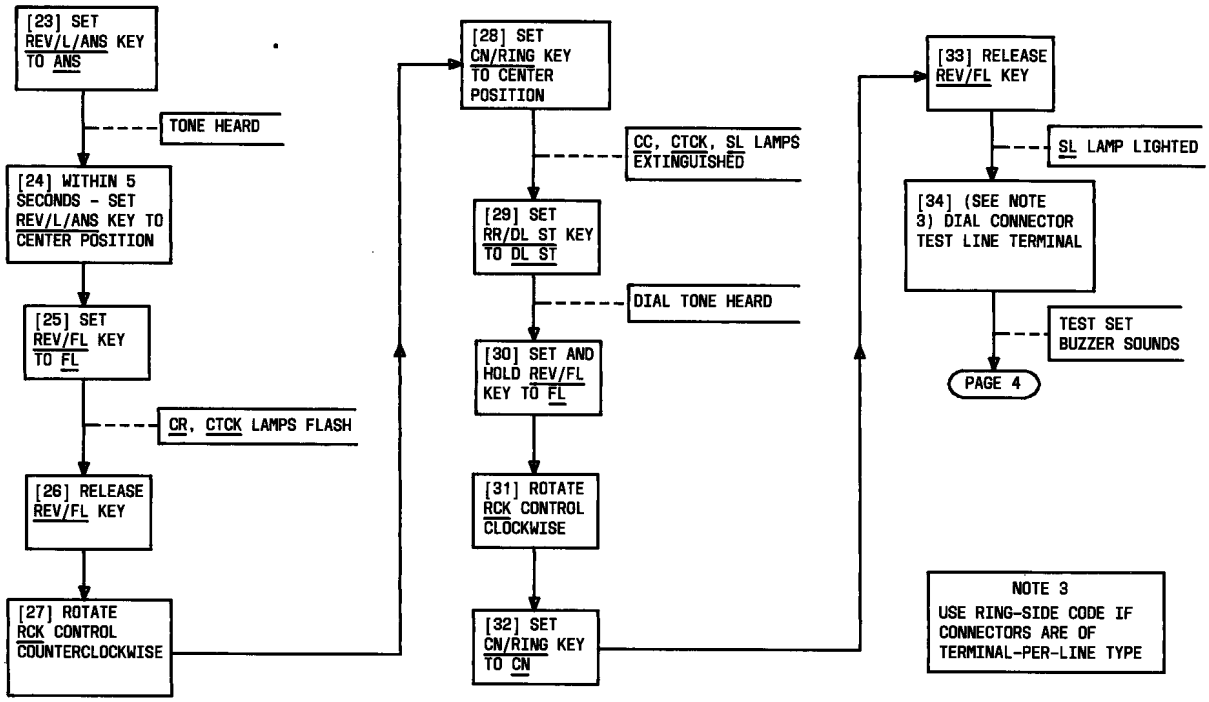


Fig. 6—Test C: Coin Collect—Loop Using Connector Test Line SD-31857-01 Fig. 3 (99 Terminal) (Sheet 3 of 4)

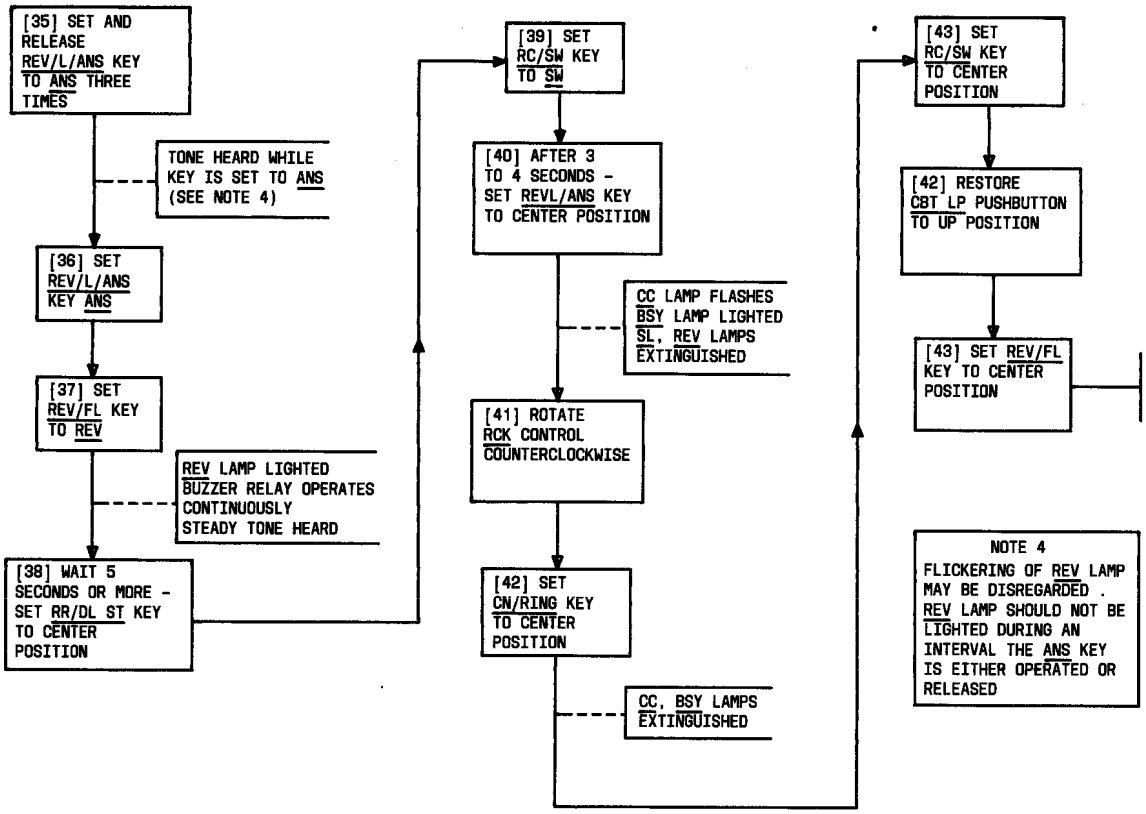


Fig. 6—Test C: Coin Collect—Loop Using Connector Test Line SD-31857-01 Fig. 3 (99 Terminal) (Sheet 4 of 4)

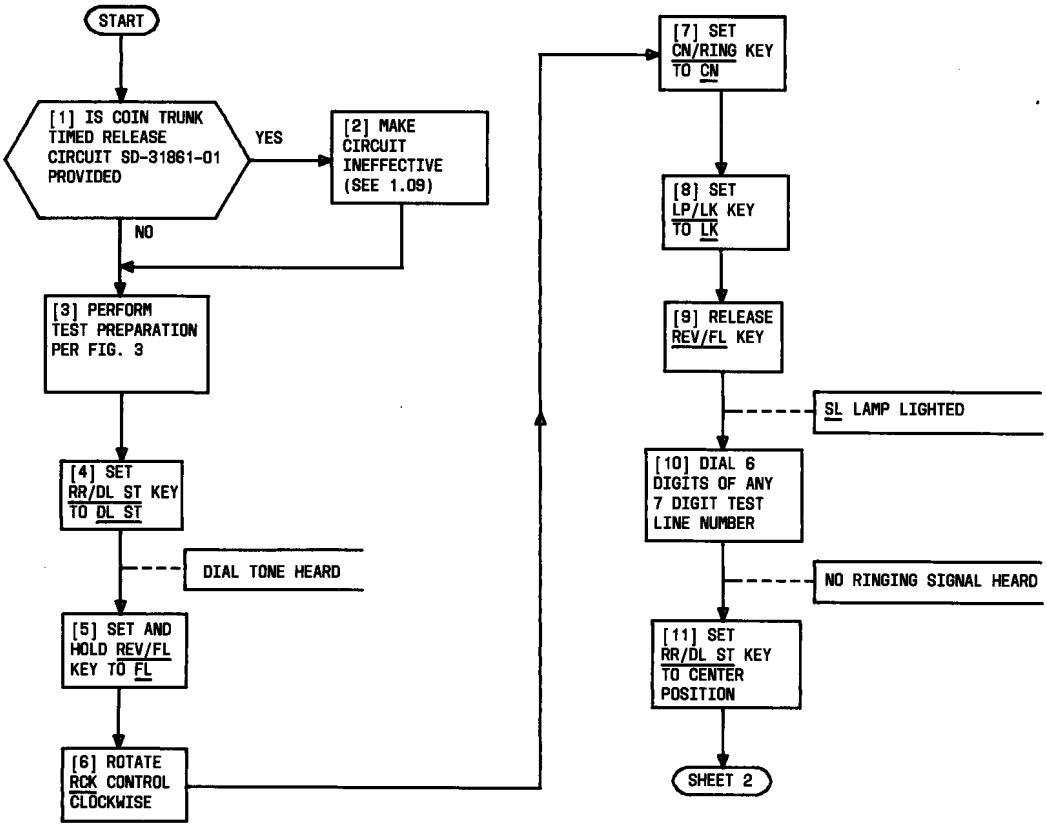


Fig. 7—Test D: Coin Return-Leak (Sheet 1 of 2)

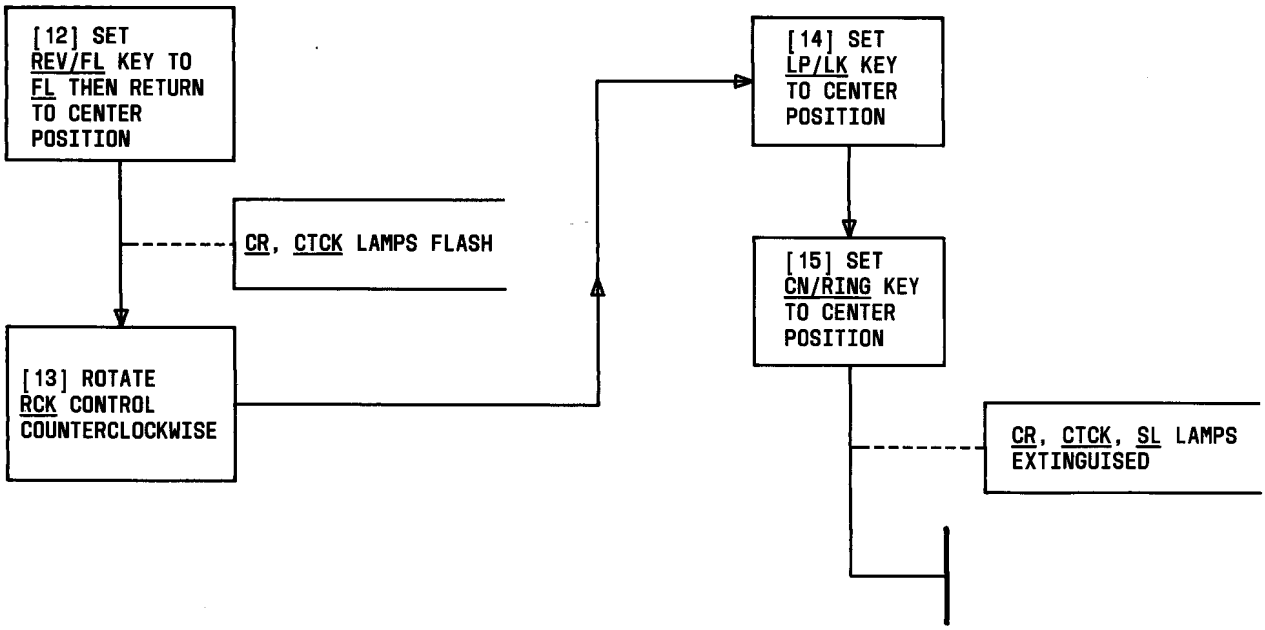


Fig. 7—Test D: Coin Return-Leak (Sheet 2 of 2)

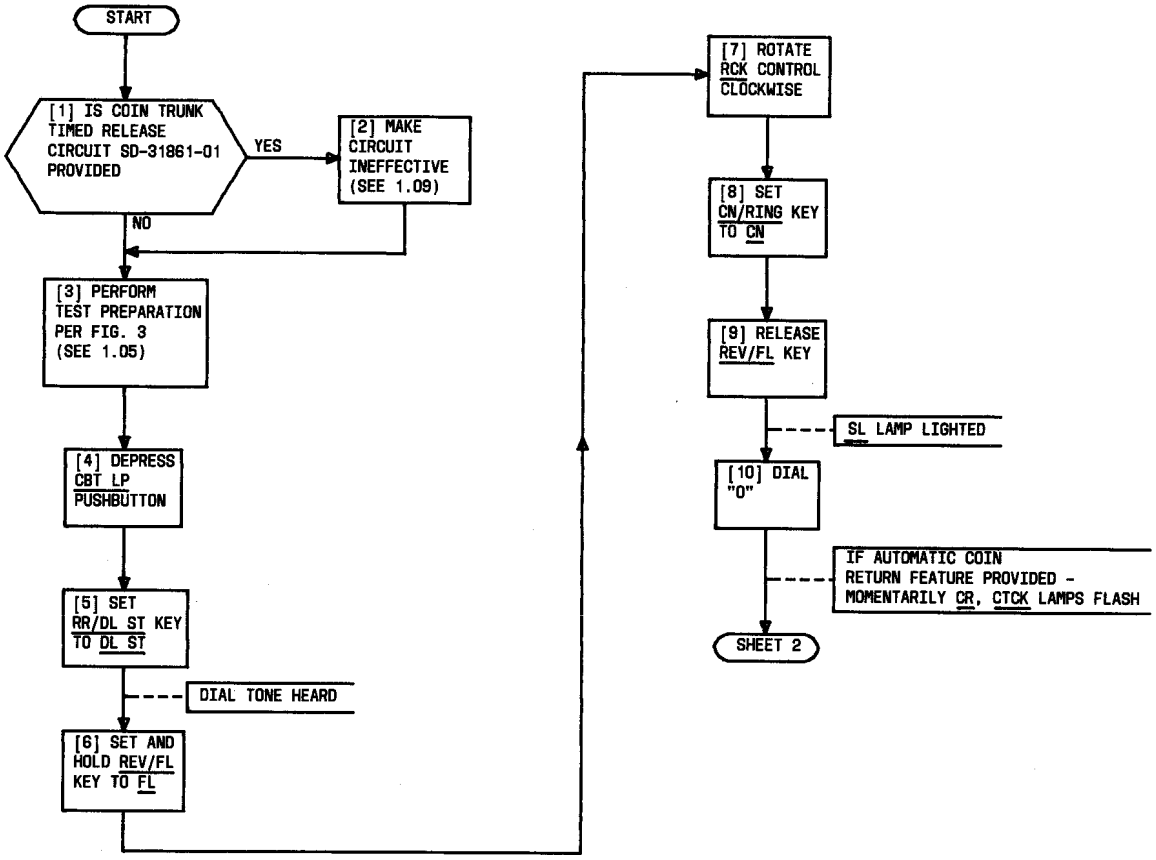


Fig. 8—Test E: Operator Cut-Through and Ringback (Sheet 1 of 3)

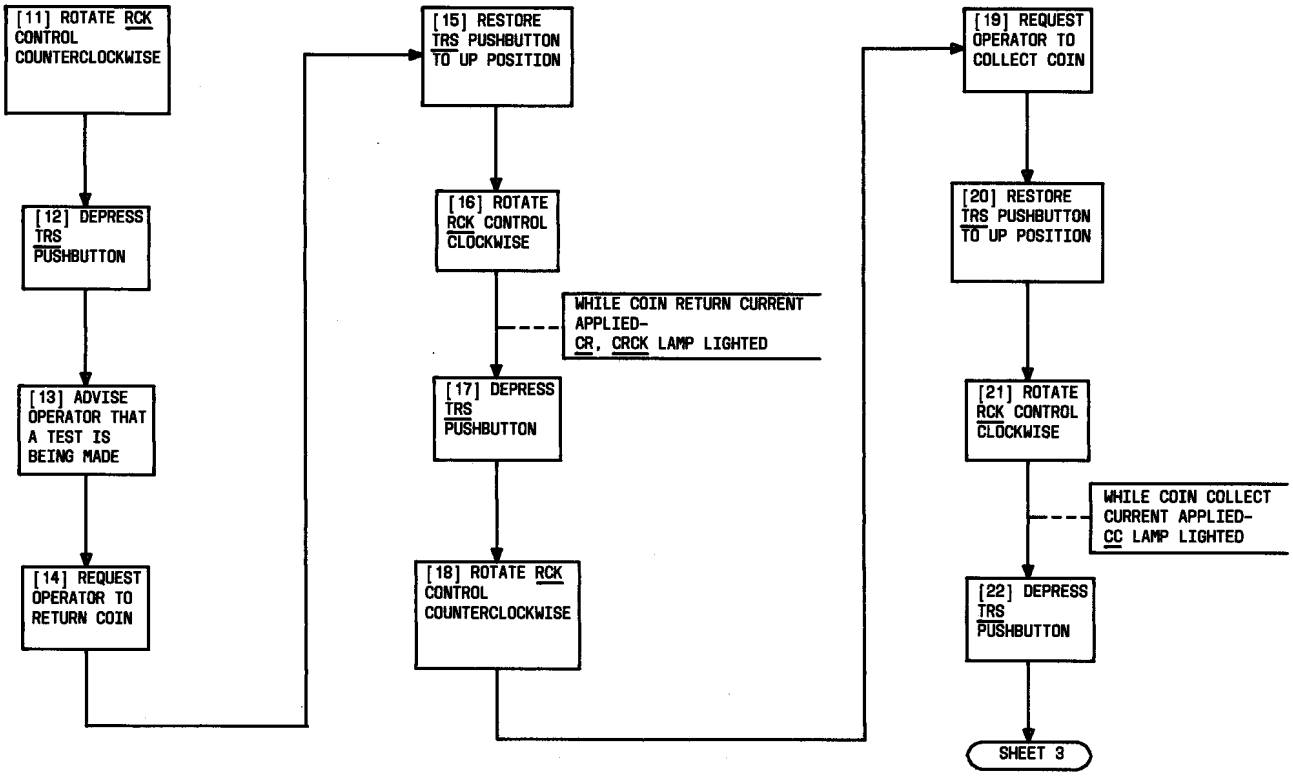


Fig. 8—Test E: Operator Cut-Through and Ringback (Sheet 2 of 3)

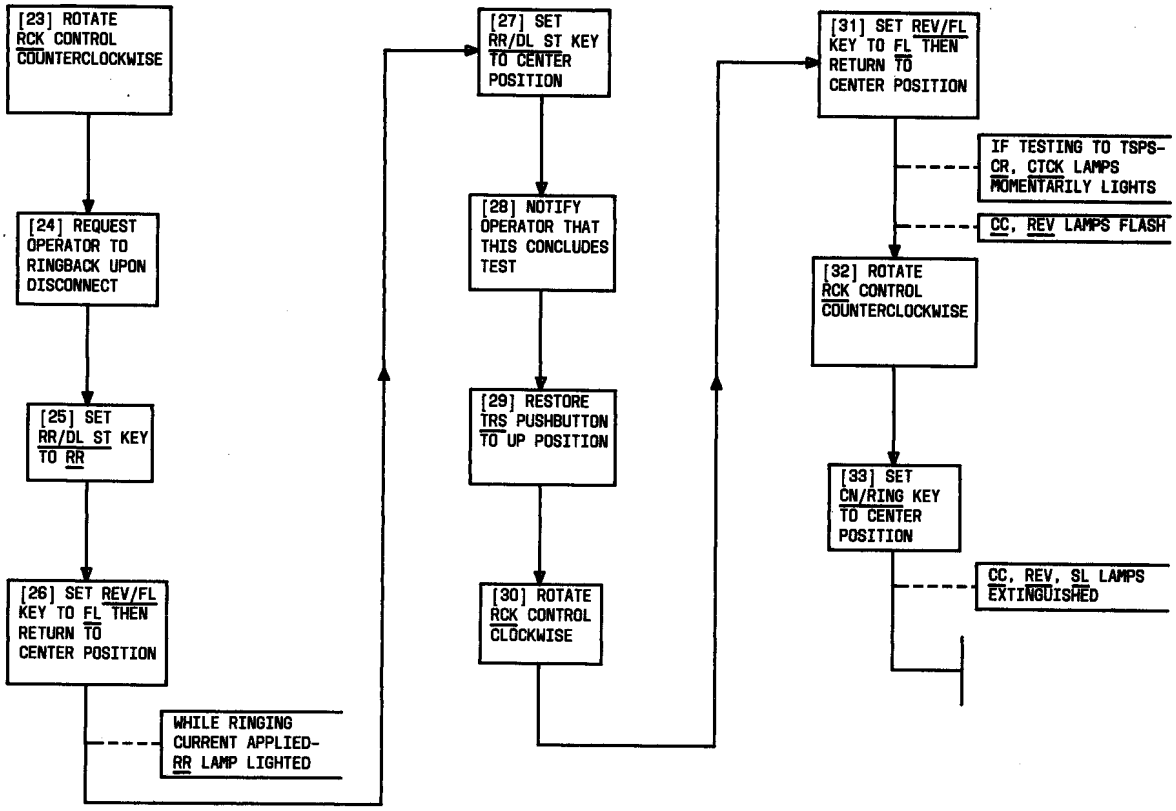


Fig. 8—Test E: Operator Cut-Through and Ringback (Sheet 3 of 3)

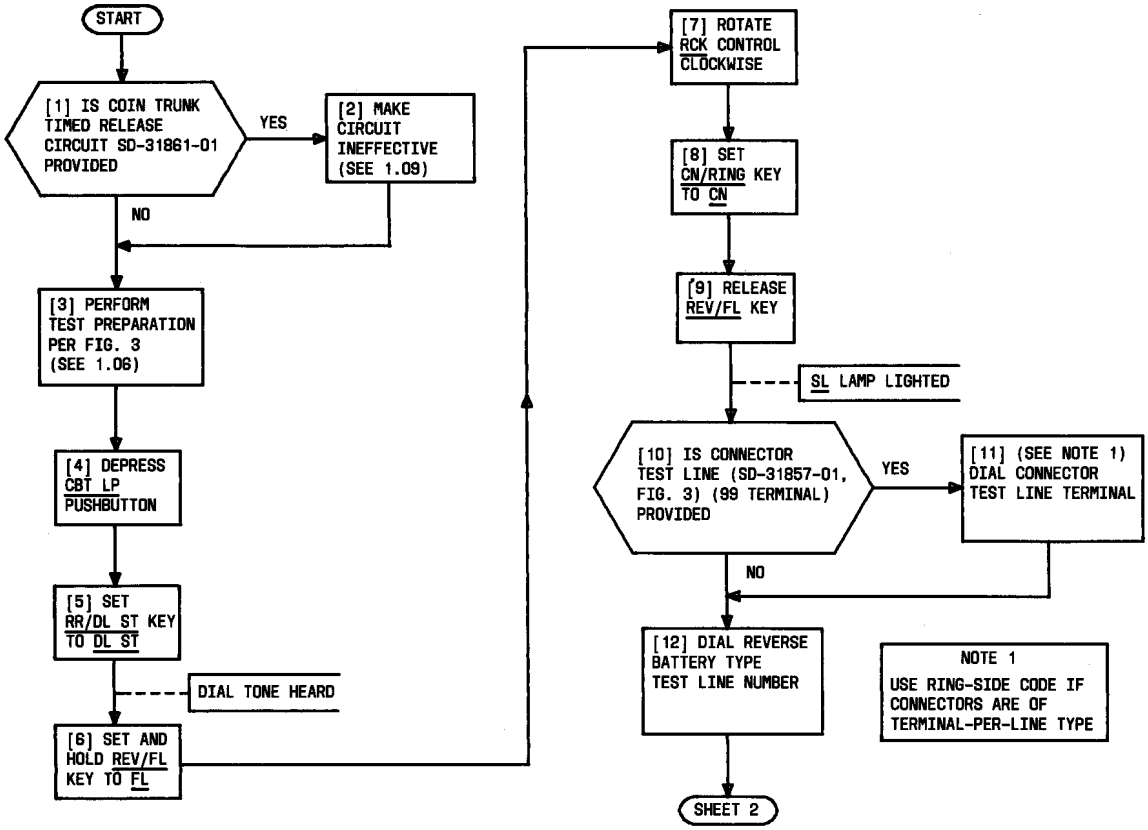


Fig. 9—Test F: P1 Relay Test (Sheet 1 of 5)

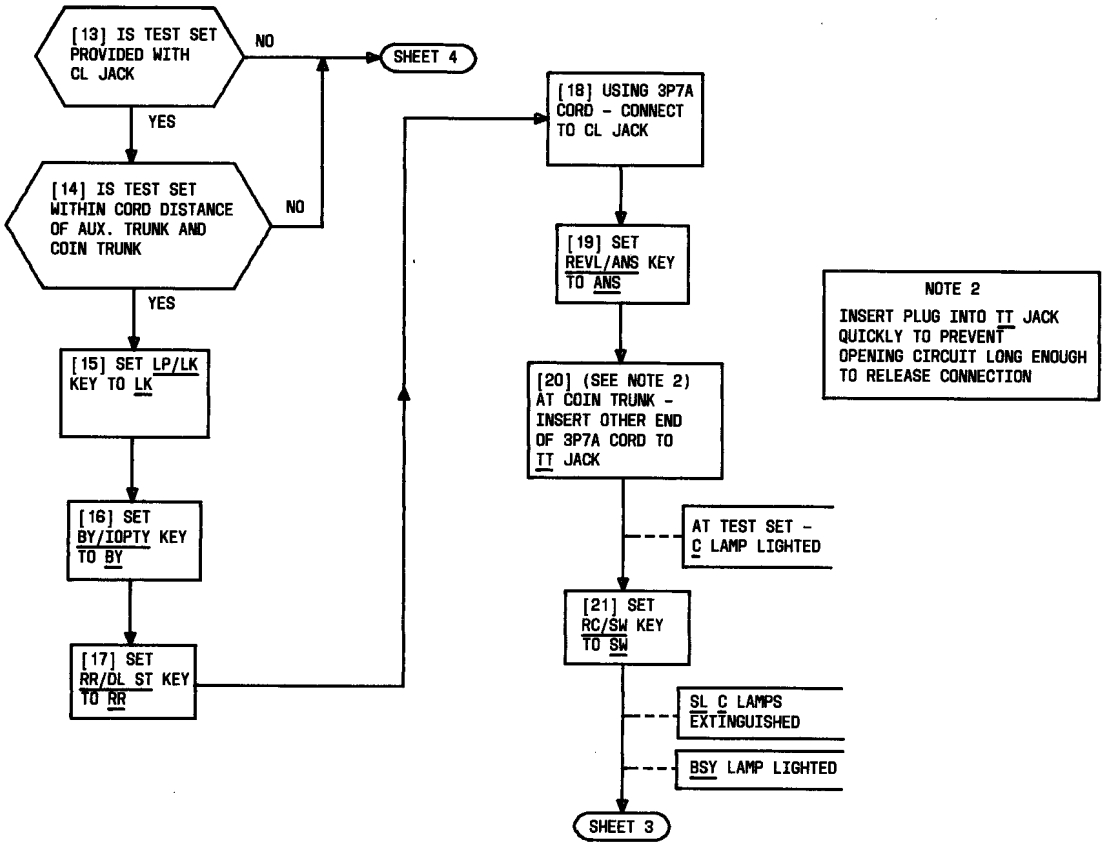


Fig. 9—Test F: P1 Relay Test (Sheet 2 of 5)

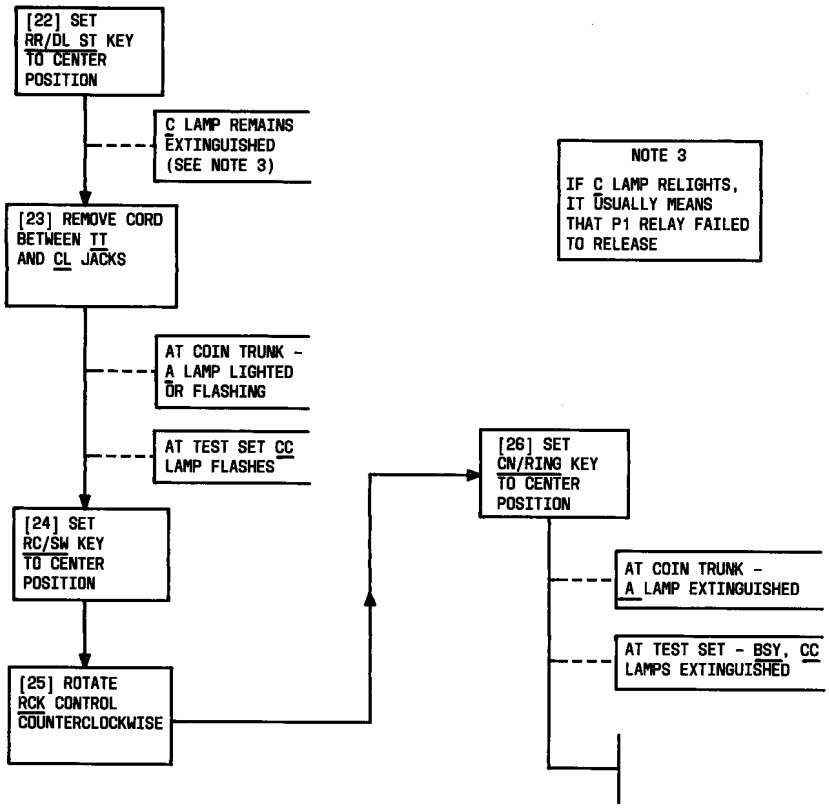


Fig. 9—Test F: P1 Relay Test (Sheet 3 of 5)

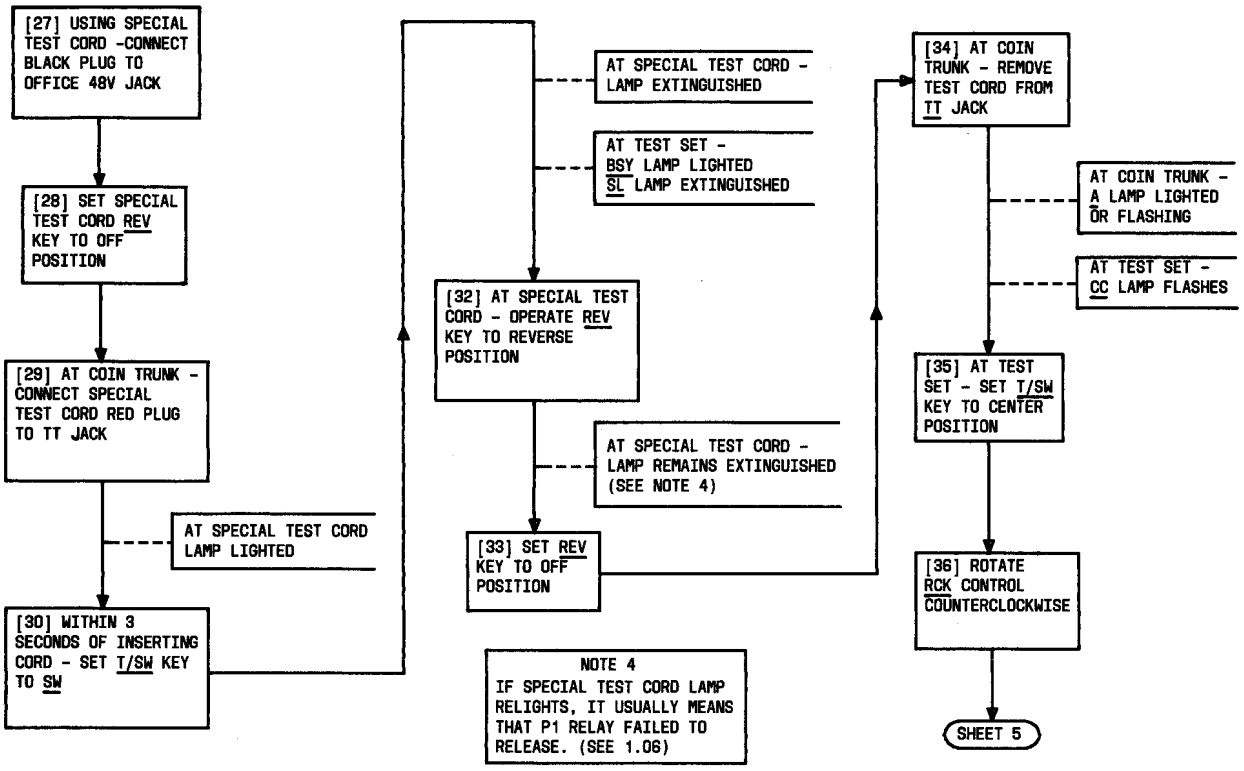


Fig. 9—Test F: P1 Relay Test (Sheet 4 of 5)

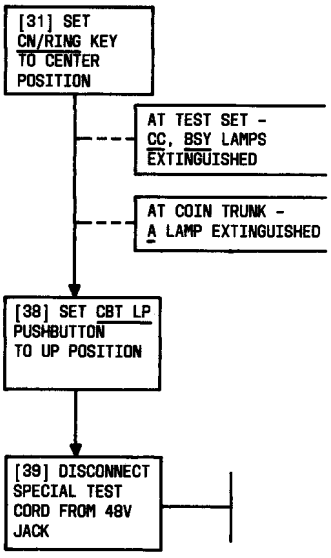


Fig. 9—Test F: P1 Relay Test (Sheet 5 of 5)

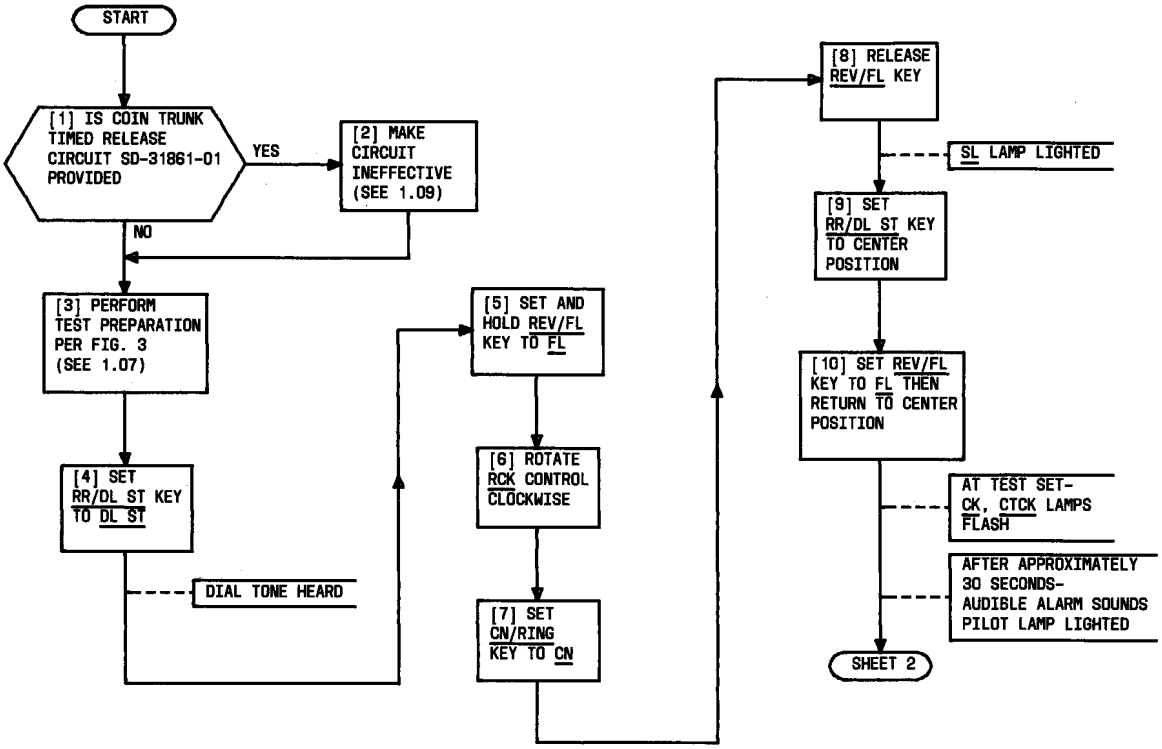


Fig. 10—Test G: Stuck-Coin Alarm Test (Sheet 1 of 2)

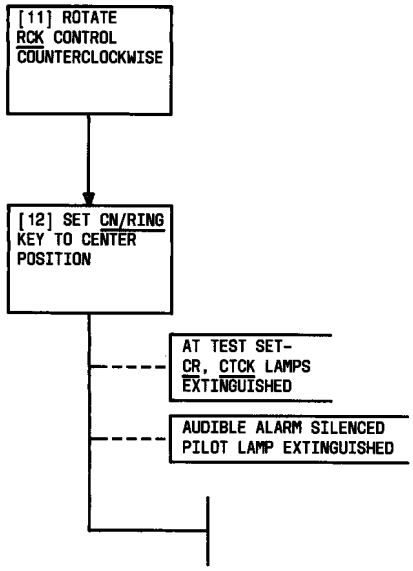


Fig. 10—Test G: Stuck-Coin Alarm Test (Sheet 2 of 2)

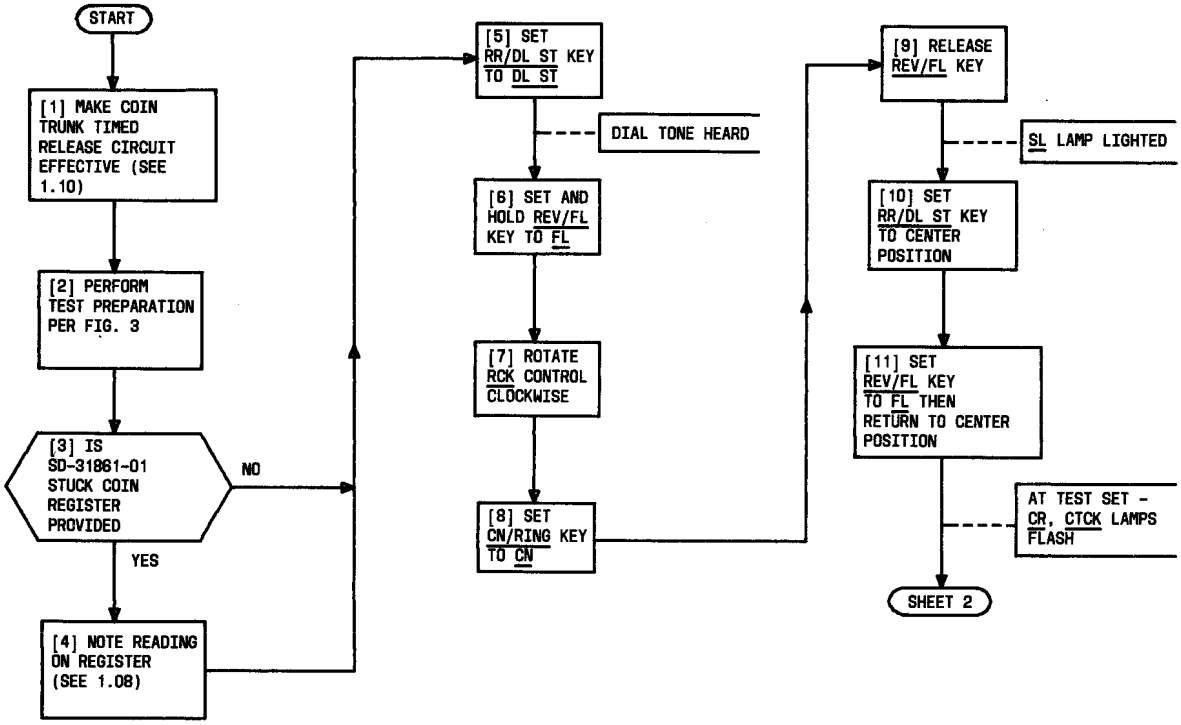


Fig. 11—Test H: Coin-Trunk-Timed-Release Circuit Test (Sheet 1 of 2)

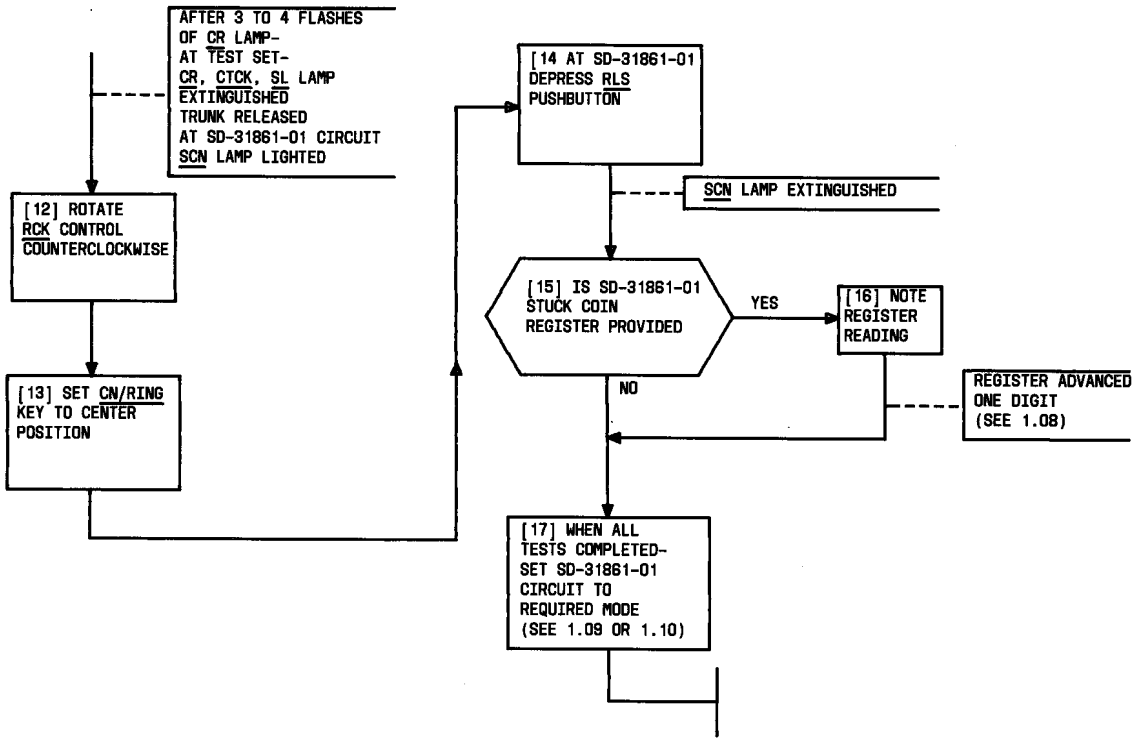


Fig. 11—Test H: Coin-Trunk-Timed-Release Circuit Test (Sheet 2 of 2)